Se	earch Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/734,354	HEO ET AL.
Examiner	Art Unit
Maki A. Angadi	1765

SEARCHED				
Class	Subclass	Date	Examiner	
438	690	6/25/2006	MA	
257	397	6/25/2006	MA	
216	80	6/25/2006	MA	
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· INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor Search	6/25/2006	MA
EAST (all data bases)	6/25/2006	МА
438/690,424,435,701,720,978; 257/397,510,522; 216/80,97	6/25/2006	MA
PLUS Search	6/25/2006	MA •
STIC Search	10/16/2006	MA
Updated above search	4/11/2007	MA